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**KEATING & BENNETT LLP**

# Fax

<b>To:</b> Examiner Baumeister	<b>From:</b> Christopher A. Bennett
<b>Fax:</b> 703-872-9319	<b>Date:</b> October 14, 2003
<b>Phone:</b> 703-306-9165	<b>Pages:</b> 16
<b>Re:</b> 09/658,732 36856.919	<b>CC:</b>

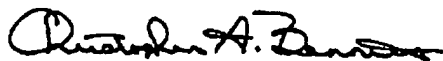
**•Comments:**

Examiner Baumeister:

Please find attached the following documents for the above-identified application:

1. Request for Reconsideration;
2. Petition for one-month Extension of Time;
3. Credit card form payment in the amount of \$110.00;
4. Terminal Disclaimer; and
5. Credit card form payment in the amount of \$110.00;

Respectfully submitted,



Christopher A. Bennett  
for  
KEATING & BENNETT, LLP  
(Registration No. 46,4710)

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OCT 14 2003

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\*22(NF)  
Reg. Recusid  
SDavis  
11/14/03CERTIFICATE OF FACSIMILE

I hereby certify that this correspondence is being transmitted to Group Art Unit 2815, 703-872-9319, addressed to: to Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Date: October 14, 2003

Sonia V. McVean  
Sonia V. McVean

**PATENT**  
36856.919

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Makoto INAI et al.	Art Unit: 2815
Serial No.: 09/658,732 ✓ 2/	Examiner: B. Baumeister
Filed: June 11, 2003 ✓	
Title: FIELD-EFFECT SEMICONDUCTOR DEVICE ✓	

## REQUEST FOR RECONSIDERATION

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Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

OCT 14 2003

Sir:

**OFFICIAL**

In response to the Office Action dated June 11, 2003, the period for response to which has been extended to October 11, 2003, by the accompanying Petition for a ONE-month Extension of Time, please reconsider the above identified application in view of the following remarks.

A listing of the claims begins on page 2 of this paper for the convenience of the Examiner. No amendments are being made by this listing.

Remarks/Arguments begin on page 6 of this paper.